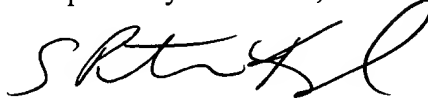


Conclusion

Applicant respectfully submits that the present application is now in condition for allowance, which action is courteously requested.

Respectfully submitted,

A handwritten signature in black ink, appearing to read 'SPK', followed by a large, stylized flourish.

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Dated: February 25, 2003

SPK/  
Enclosures



MARKED UP VERSION TO SHOW CHANGES MADE

CLAIMS

1. (Amended) A microscope assemblage[, in particular] for confocal scanning microscopy[,] compris[es]ing:

a light source[(1)] for illuminating a top side of a specimen[(6),]; said top side facing said light source;

at least one fluorescent-light detector[(11,14)] arranged on a bottom side of the specimen, said bottom side facing away from said light source, said fluorescent detector detecting [for the detection of] fluorescent light [(10,13)] generated [in the] by said specimen [(6)]; and,

at least one transmitted light detector [(16)] for detecting [the detection of transmitted light (15) passing] light transmitted through the specimen [(6), wherein the fluorescent light and transmitted light detectors (11, 14, 16) are arranged to enable simultaneous detection of fluorescent and transmitted light (10, 13;15)]; said fluorescent and said transmitted detectors simultaneously detecting fluorescent and transmitted light.

3. (Amended) The microscope assemblage as defined in Claim 1 [2], characterized in that at least one transmitted-light detector (16) is arranged on the side of the specimen (6) facing away from the light source (1).

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11. (Amended) The microscope assemblage as defined in Claim 1 [2], characterized in that a scanning device (4) is arranged on the side of the specimen (6) facing toward the light source (1).

29. (Amended) A microscope assemblage [, in particular] for confocal scanning microscopy [,comprises] comprising:

a light source (1) for illuminating a specimen (6);

at least one fluorescent-light detector (11, 14) for the detection of fluorescent light (10, 13) generated in the specimen (6), wherein the specimen (6) defines a top side (6a) facing the light source (1) and a bottom side (6b) facing away from the light source (1);

at least one transmitted-light detector (16) for the detection of transmitted light (15) passing through the specimen (6); and,

an additional light source (21) operatively arranged on the side of the specimen (6) facing away from the light source (1) and arranged for illuminating said specimen.

31. (Amended) The microscope assemblage as defined in Claim 29, characterized in that an optical system is a member selected from the group consisting of a sector optical system, a sector polarization optical system, a sector stop, a sector phase stop and a sector phase filter, said optical system associated with said additional light source. [, which consists essentially of a sector optical system, a sector polarization optical system, a sector stop (20), a sector phase stop and a sector phase filter, is associated with the additional light source (21)]

32. (Amended) The microscope assemblage as defined in Claim 31, characterized in that the optical system is arranged in a [the] Fourier plane before the additional light source (21).

42. (Amended) The microscope assemblage as defined in Claim 29, characterized in that at least one detector (17) is arranged on the side of the specimen (6) facing toward the light source (1), [preferably] on the side of the scanning device (4) facing away from the specimen (6).